

**4.7A, 30V, 0.031 Ohm, N-Channel, Logic Level UltraFET Power MOSFET**


This N-Channel power MOSFET is manufactured using the innovative UltraFET process. This advanced process technology achieves the

lowest possible on-resistance per silicon area, resulting in outstanding performance. This device is capable of withstanding high energy in the avalanche mode and the diode exhibits very low reverse recovery time and stored charge. It was designed for use in applications where power efficiency is important, such as switching regulators, switching converters, motor drivers, relay drivers, low-voltage bus switches, and power management in portable and battery-operated products.

Formerly developmental type TA76113.

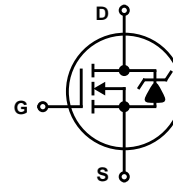
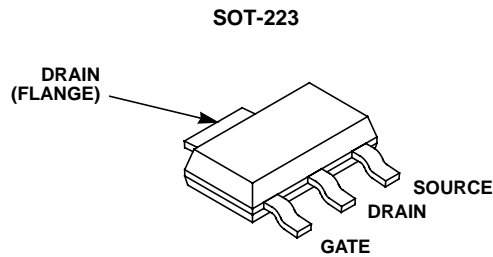
**Ordering Information**

PART NUMBER	PACKAGE	BRAND
HUF76113T3ST	SOT-223	76113

NOTE: HUF76113T3ST is available only in tape and reel.

**Features**

- Logic Level Gate Drive
- 4.7A, 30V
- Ultra Low On-Resistance,  $r_{DS(ON)} = 0.031\Omega$
- Temperature Compensating PSPICE® Model
- Temperature Compensating SABER™ Model
- Thermal Impedance SPICE Model
- Thermal Impedance SABER Model
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- Related Literature
  - TB334, "Guidelines for Soldering Surface Mount Components to PC Boards"

**Symbol**

**Packaging**


# HUF76113T3ST

## Absolute Maximum Ratings $T_A = 25^\circ\text{C}$ , Unless Otherwise Specified

	HUF76113T3ST	UNITS
Drain to Source Voltage (Note 1) . . . . .	$V_{DSS}$	30 V
Drain to Gate Voltage ( $R_{GS} = 20\text{k}\Omega$ ) (Note 1) . . . . .	$V_{DGR}$	30 V
Gate to Source Voltage . . . . .	$V_{GS}$	$\pm 16$ V
<b>Drain Current</b>		
Continuous ( $T_A = 25^\circ\text{C}$ , $V_{GS} = 10\text{V}$ ) (Figure 2) (Note 2) . . . . .	$I_D$	4.7 A
Continuous ( $T_A = 100^\circ\text{C}$ , $V_{GS} = 5\text{V}$ ) (Note 2) . . . . .	$I_D$	2.7 A
Continuous ( $T_A = 100^\circ\text{C}$ , $V_{GS} = 4.5\text{V}$ ) (Note 2) . . . . .	$I_D$	2.6 A
Pulsed Drain Current . . . . .	$I_{DM}$	Figure 4
Pulsed Avalanche Rating . . . . .	$E_{AS}$	Figure 6
Power Dissipation (Note 2) . . . . .	$P_D$	1.1 W
Derate Above $25^\circ\text{C}$ . . . . .		0.0091 W/ $^\circ\text{C}$
Operating and Storage Temperature . . . . .	$T_J, T_{STG}$	-55 to 150 $^\circ\text{C}$
<b>Maximum Temperature for Soldering</b>		
Leads at 0.063in (1.6mm) from Case for 10s . . . . .	$T_L$	300 $^\circ\text{C}$
Package Body for 10s, See Techbrief 334 . . . . .	$T_{pkg}$	260 $^\circ\text{C}$

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

### NOTE:

- $T_J = 25^\circ\text{C}$  to  $150^\circ\text{C}$ .

## Electrical Specifications $T_A = 25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
<b>OFF STATE SPECIFICATIONS</b>						
Drain to Source Breakdown Voltage	$BV_{DSS}$	$I_D = 250\mu\text{A}$ , $V_{GS} = 0\text{V}$ (Figure 12)	30	-	-	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 25\text{V}$ , $V_{GS} = 0\text{V}$	-	-	1	$\mu\text{A}$
		$V_{DS} = 25\text{V}$ , $V_{GS} = 0\text{V}$ , $T_C = 150^\circ\text{C}$	-	-	250	$\mu\text{A}$
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 16\text{V}$	-	-	$\pm 100$	nA
<b>ON STATE SPECIFICATIONS</b>						
Gate to Source Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}$ , $I_D = 250\mu\text{A}$ (Figure 11)	1	-	3	V
Drain to Source On Resistance	$r_{DS(ON)}$	$I_D = 4.7\text{A}$ , $V_{GS} = 10\text{V}$ (Figure 9, 10)	-	0.027	0.031	W
		$I_D = 2.7\text{A}$ , $V_{GS} = 5\text{V}$ (Figure 9)	-	0.033	0.038	W
		$I_D = 2.6\text{A}$ , $V_{GS} = 4.5\text{V}$ (Figure 9)	-	0.035	0.040	W
<b>THERMAL SPECIFICATIONS</b>						
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	Pad Area = $0.173\text{ in}^2$ (Note 2)	-	-	110	$^\circ\text{C/W}$
		Pad Area = $0.068\text{ in}^2$ (See TB377)	-	-	133	$^\circ\text{C/W}$
		Pad Area = $0.026\text{ in}^2$ (See TB377)	-	-	157	$^\circ\text{C/W}$
<b>SWITCHING SPECIFICATIONS (<math>V_{GS} = 4.5\text{V}</math>)</b>						
Turn-On Time	$t_{ON}$	$V_{DD} = 15\text{V}$ , $I_D \cong 2.6\text{A}$ , $R_L = 5.8\Omega$ , $V_{GS} = 4.5\text{V}$ , $R_{GS} = 18\Omega$ (Figure 15)	-	-	90	ns
Turn-On Delay Time	$t_{d(ON)}$		-	12	-	ns
Rise Time	$t_r$		-	46	-	ns
Turn-Off Delay Time	$t_{d(OFF)}$		-	31	-	ns
Fall Time	$t_f$		-	31	-	ns
Turn-Off Time	$t_{OFF}$		-	-	95	ns

# HUF76113T3ST

## Electrical Specifications $T_A = 25^\circ\text{C}$ , Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS	
<b>SWITCHING SPECIFICATIONS</b> ( $V_{GS} = 10\text{V}$ )							
Turn-On Time	$t_{ON}$	$V_{DD} = 15\text{V}$ , $I_D \cong 4.7\text{A}$ , $R_L = 3.2\Omega$ , $V_{GS} = 10\text{V}$ , $R_{GS} = 9.1\Omega$ (Figure 16)	-	-	40	ns	
Turn-On Delay Time	$t_{d(ON)}$		-	4	-	ns	
Rise Time	$t_r$		-	21	-	ns	
Turn-Off Delay Time	$t_{d(OFF)}$		-	31	-	ns	
Fall Time	$t_f$		-	25	-	ns	
Turn-Off Time	$t_{OFF}$		-	-	85	ns	
<b>GATE CHARGE SPECIFICATIONS</b>							
Total Gate Charge	$Q_{g(TOT)}$	$V_{GS} = 0\text{V to } 10\text{V}$	$V_{DD} = 15\text{V}$ , $I_D \cong 2.7\text{A}$ , $R_L = 5.5\Omega$ $I_{g(REF)} = 1.0\text{mA}$ (Figure 14)	-	17.0	20.5	nC
Gate Charge at 5V	$Q_{g(5)}$	$V_{GS} = 0\text{V to } 5\text{V}$		-	9.5	11.5	nC
Threshold Gate Charge	$Q_{g(TH)}$	$V_{GS} = 0\text{V to } 1\text{V}$		-	0.73	0.90	nC
Gate to Source Gate Charge	$Q_{gs}$			-	1.50	-	nC
Gate to Drain "Miller" Charge	$Q_{gd}$			-	4.30	-	nC
<b>CAPACITANCE SPECIFICATIONS</b>							
Input Capacitance	$C_{ISS}$	$V_{DS} = 25\text{V}$ , $V_{GS} = 0\text{V}$ , $f = 1\text{MHz}$ (Figure 13)	-	625	-	pF	
Output Capacitance	$C_{OSS}$		-	310	-	pF	
Reverse Transfer Capacitance	$C_{RSS}$		-	60	-	pF	

### NOTES:

- Rated with  $R_{\theta JA} = 110^\circ\text{C/W}$  measured using FR-4 board with 0.173 in<sup>2</sup> copper at 1000 seconds.

## Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage	$V_{SD}$	$I_{SD} = 4.7\text{A}$	-	-	1.25	V
		$I_{SD} = 2.7\text{A}$	-	-	1.00	V
Reverse Recovery Time	$t_{rr}$	$I_{SD} = 2.7\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	44	ns
Reverse Recovered Charge	$Q_{RR}$	$I_{SD} = 2.7\text{A}$ , $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	46	nC

## Typical Performance Curves

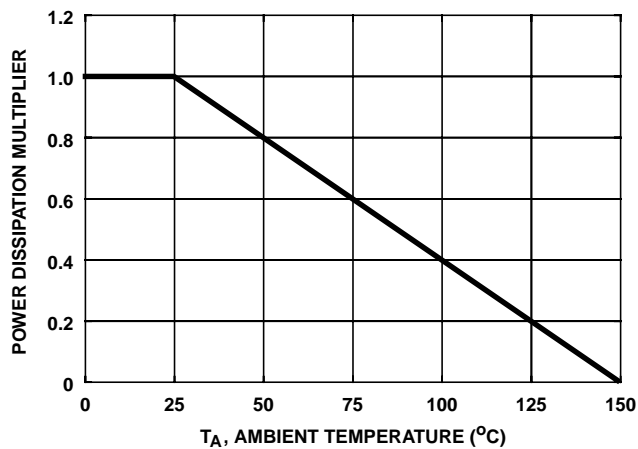


FIGURE 1. NORMALIZED POWER DISSIPATION vs AMBIENT TEMPERATURE

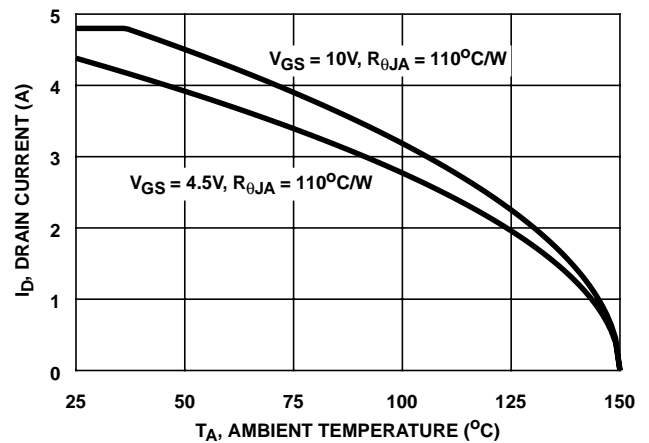


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs AMBIENT TEMPERATURE

Typical Performance Curves (Continued)

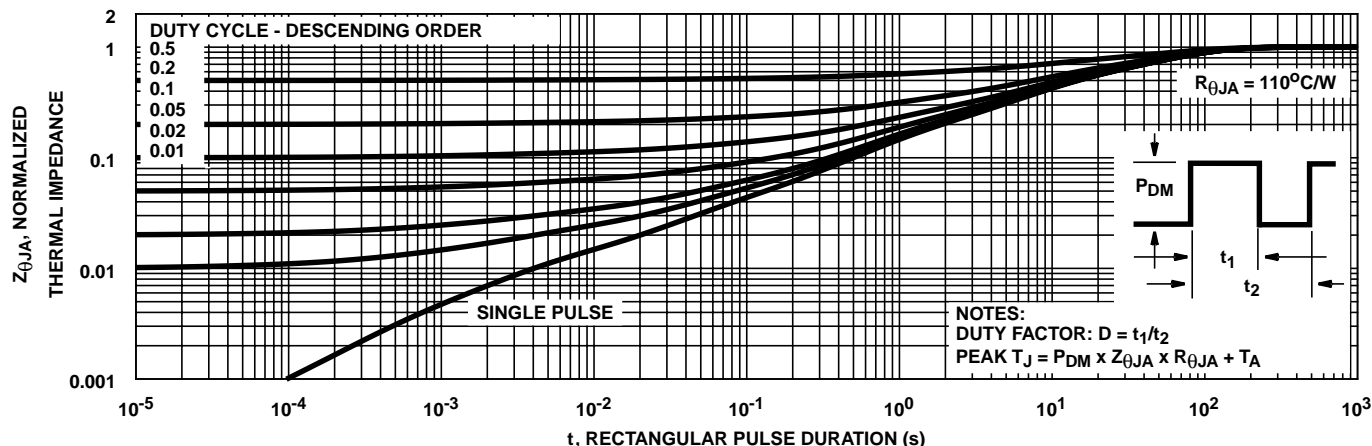


FIGURE 3. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

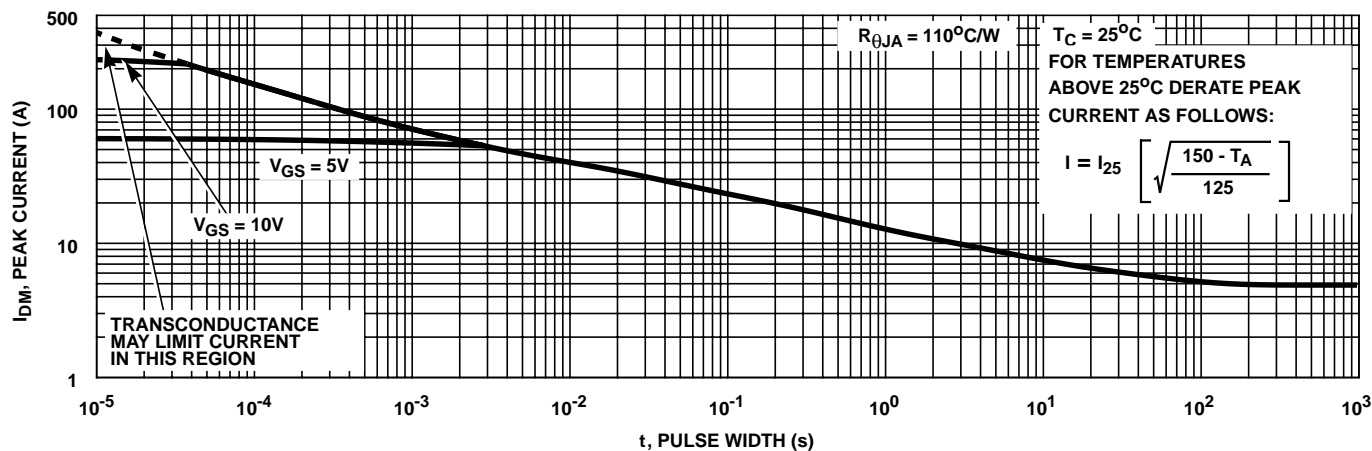


FIGURE 4. PEAK CURRENT CAPABILITY

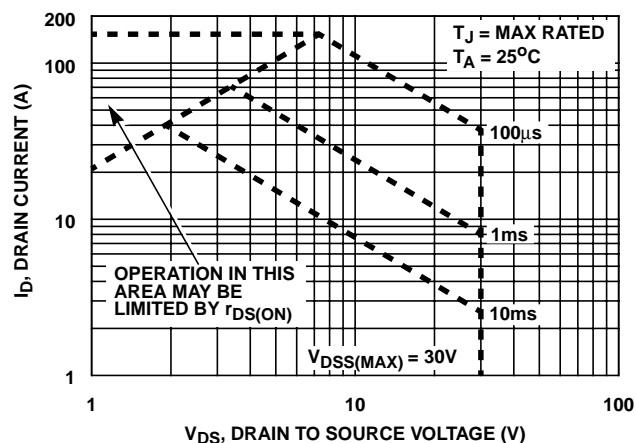
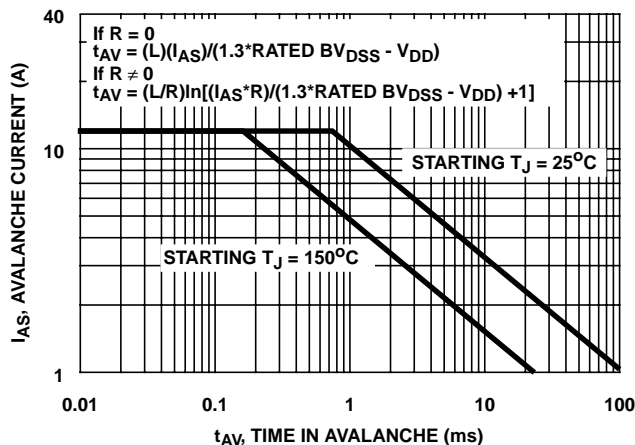


FIGURE 5. FORWARD BIAS SAFE OPERATING AREA



NOTE: Refer to Intersil Application Notes AN9321 and AN9322.

FIGURE 6. UNCLAMPED INDUCTIVE SWITCHING CAPABILITY

Typical Performance Curves (Continued)

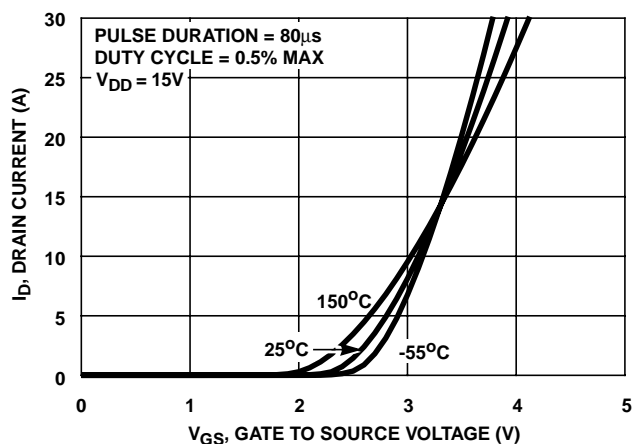


FIGURE 7. TRANSFER CHARACTERISTICS

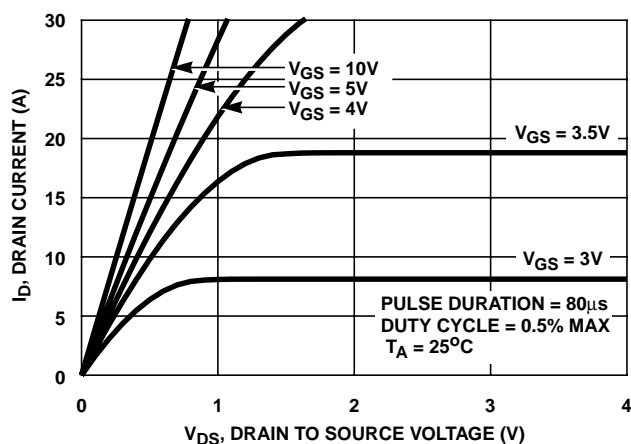


FIGURE 8. SATURATION CHARACTERISTICS

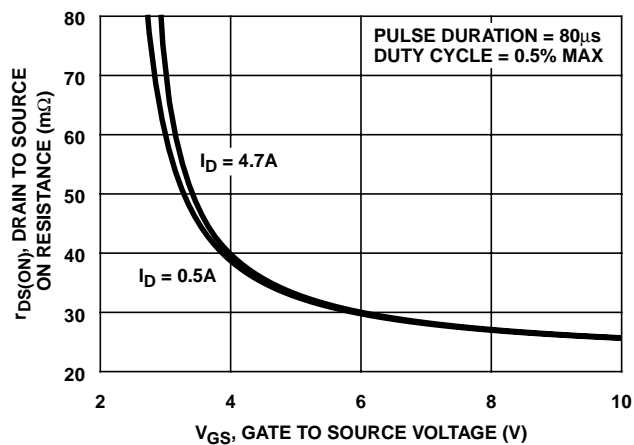


FIGURE 9. DRAIN TO SOURCE ON RESISTANCE vs GATE VOLTAGE AND DRAIN CURRENT

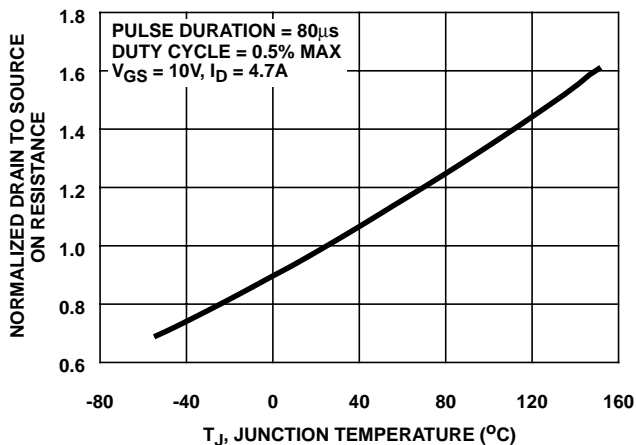


FIGURE 10. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

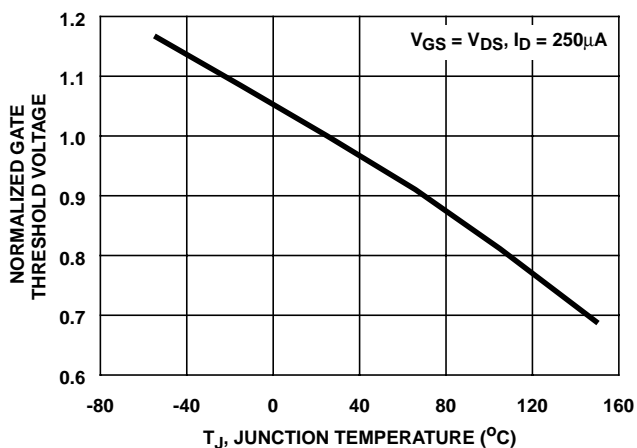


FIGURE 11. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

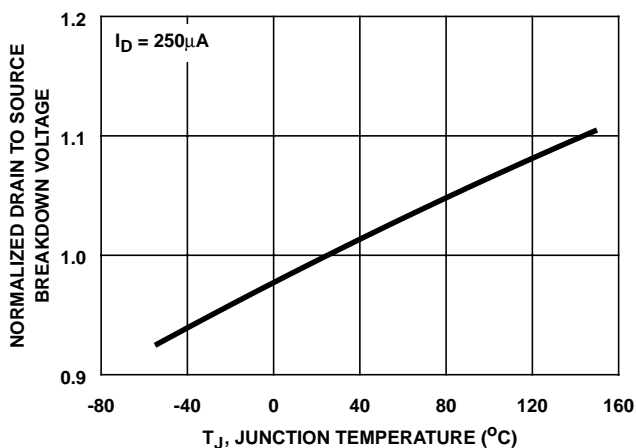


FIGURE 12. NORMALIZED DRAIN TO SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

Typical Performance Curves (Continued)

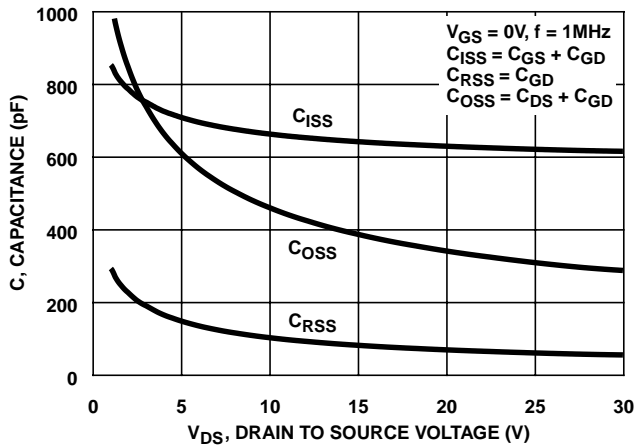
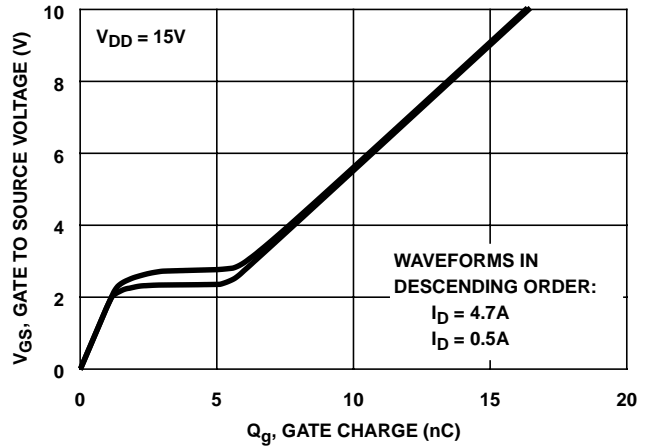


FIGURE 13. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE



NOTE: Refer to Intersil Application Notes AN7254 and AN7260.

FIGURE 14. GATE CHARGE WAVEFORMS FOR CONSTANT GATE CURRENT

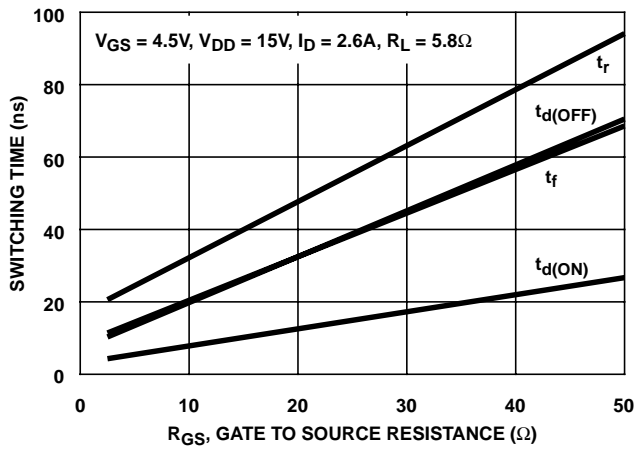


FIGURE 15. SWITCHING TIME vs GATE RESISTANCE

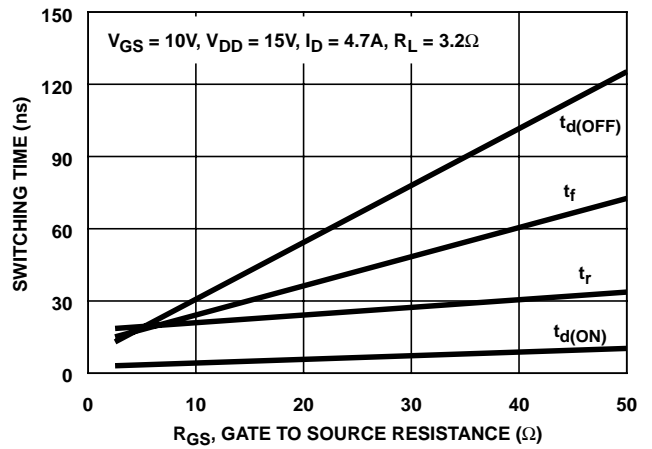


FIGURE 16. SWITCHING TIME vs GATE RESISTANCE

Test Circuits and Waveforms

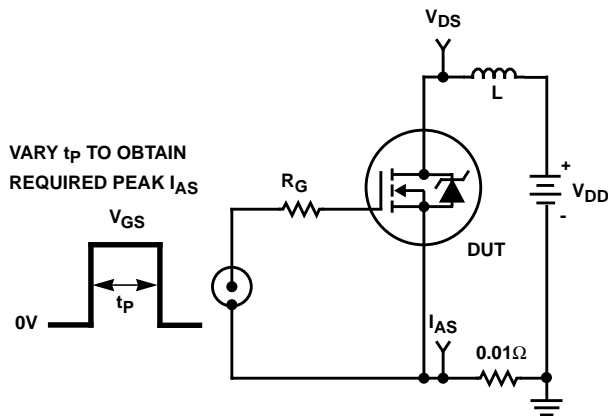


FIGURE 17. UNCLAMPED ENERGY TEST CIRCUIT

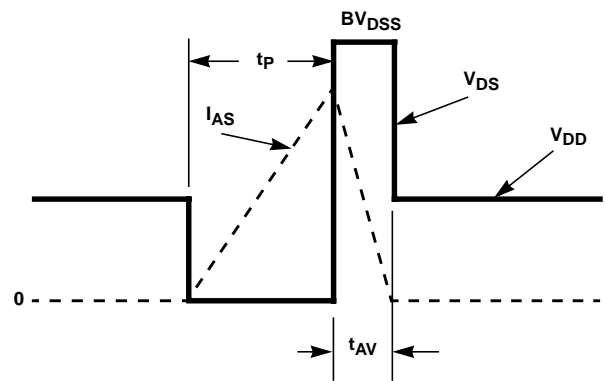


FIGURE 18. UNCLAMPED ENERGY WAVEFORMS

Test Circuits and Waveforms (Continued)

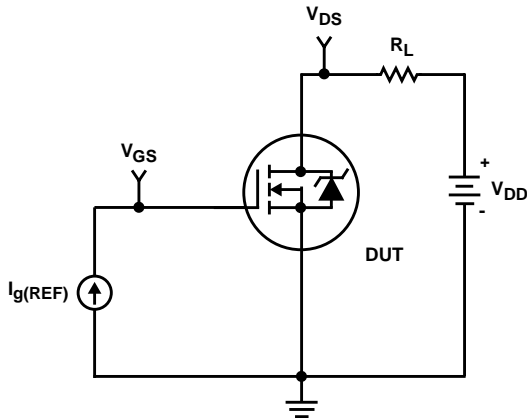


FIGURE 19. GATE CHARGE TEST CIRCUIT

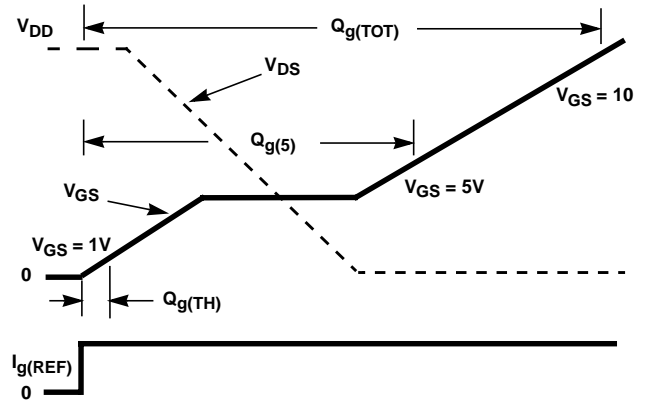


FIGURE 20. GATE CHARGE WAVEFORMS

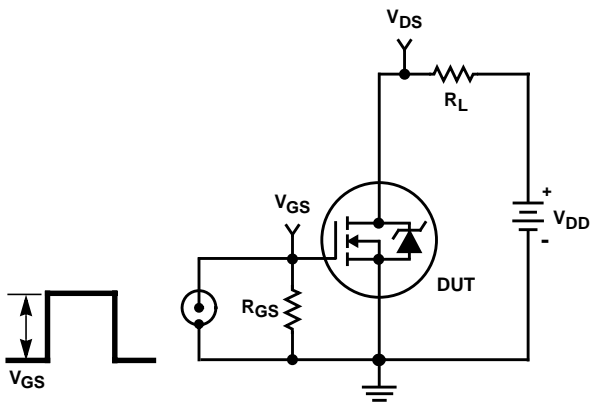


FIGURE 21. SWITCHING TIME TEST CIRCUIT

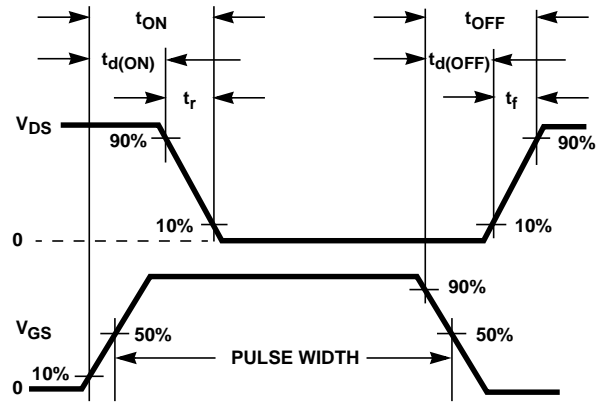


FIGURE 22. SWITCHING TIME WAVEFORM

**Thermal Resistance vs. Mounting Pad Area**

The maximum rated junction temperature,  $T_{JM}$ , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation,  $P_{DM}$ , in an application. Therefore the application's ambient temperature,  $T_A$  ( $^{\circ}C$ ), and thermal resistance  $R_{\theta JA}$  ( $^{\circ}C/W$ ) must be reviewed to ensure that  $T_{JM}$  is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{Z_{\theta JA}} \quad (EQ. 1)$$

In using surface mount devices such as the SOT-223 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of  $P_{DM}$  is complex and influenced by many factors:

1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
2. The number of copper layers and the thickness of the board.
3. The use of external heat sinks.
4. The use of thermal vias.
5. Air flow and board orientation.
6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Intersil provides thermal information to assist the designer's preliminary application evaluation. Figure 23 defines the  $R_{\theta JA}$  for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Intersil device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve. Displayed on the curve are  $R_{\theta JA}$  values listed in the Electrical Specifications table. The points were chosen to depict the compromise between the copper board area, the thermal resistance and ultimately the power dissipation,  $P_{DM}$ . The smallest areas represent

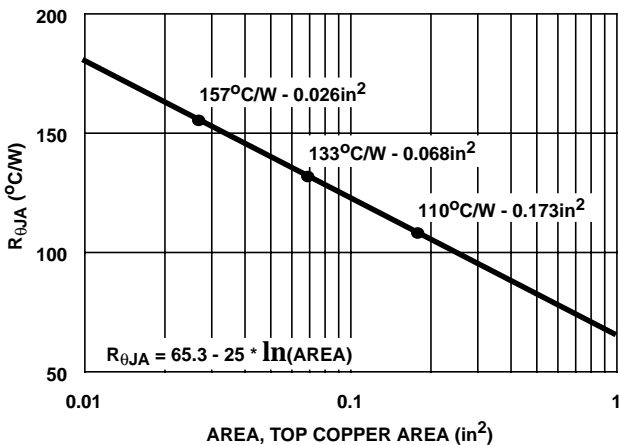


FIGURE 23. THERMAL RESISTANCE vs MOUNTING PAD AREA

the minimum bond pad area and the package outline area respectively as determined from the package diagram

Thermal resistances corresponding to other copper areas can be obtained from Figure 23 or by calculation using Equation 2.  $R_{\theta JA}$  is defined as the natural log of the area times a coefficient added to a constant. The area, in square inches is the top copper area including the gate and source pads.

$$R_{\theta JA} = 65.3 - 25 \times \ln(\text{Area}) \quad (\text{EQ. 2})$$

The transient thermal impedance ( $Z_{\theta JA}$ ) is also effected by varied top copper board area. Figure 24 shows the effect of copper pad area on single pulse transient thermal impedance. Each trace represents a copper pad area in square inches corresponding to the descending list in the graph. Spice and SABER thermal models are provided for each of the listed pad areas.

Copper pad area has no perceivable effect on transient thermal impedance for pulse widths less than 100ms. For pulse widths less than 100ms the transient thermal impedance is determined by the die and package. Therefore, C THERM1 through C THERM5 and R THERM1 through R THERM5 remain constant for each of the thermal models. A listing of the model component values is available in Table 1.

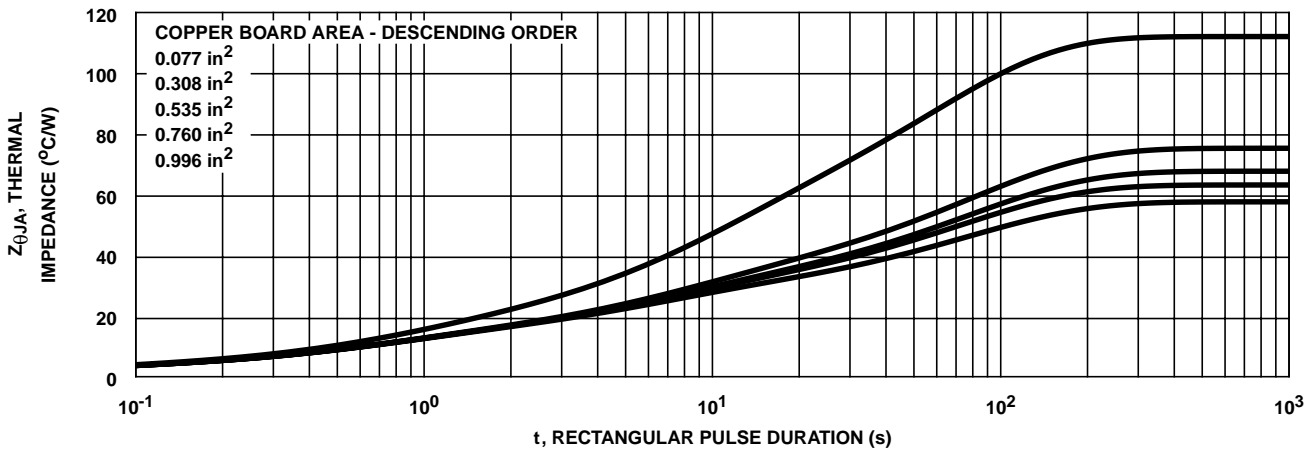


FIGURE 24. THERMAL IMPEDANCE vs MOUNTING PAD AREA



# HUF76113T3ST

## PSPICE Electrical Model

.SUBCKT HUF76113T3 2 1 3 ; REV August 1998

CA 12 8 8.7e-10  
 CB 15 14 8.7e-10  
 CIN 6 8 5.6e-10

DBODY 7 5 DBODYMOD  
 DBREAK 5 11 DBREAKMOD  
 DPLCAP 10 5 DPLCAPMOD

EBREAK 11 7 17 18 34.3  
 EDS 14 8 5 8 1  
 EGS 13 8 6 8 1  
 ESG 6 10 6 8 1  
 EVTHRES 6 21 19 8 1  
 EVTEMP 20 6 18 22 1

IT 8 17 1

LDRAIN 2 5 1e-9  
 LGATE 1 9 1.69e-9  
 LSOURCE 3 7 4.1e-10

MMED 16 6 8 8 MMEDMOD  
 MSTRO 16 6 8 8 MSTROMOD  
 MWEAK 16 21 8 8 MWEAKMOD

RBREAK 17 18 RBREAKMOD 1  
 RDRAIN 50 16 RDRAINMOD 9.2e-3  
 RGATE 9 20 2.5  
 RLDRAIN 2 5 10  
 RLGATE 1 9 16.9  
 RLSOURCE 3 7 4.1  
 RSLC1 5 51 RSLCMOD 1e-6  
 RSLC2 5 50 1e3  
 RSOURCE 8 7 RSOURCEMOD 12.5e-3  
 RVTHRES 22 8 RVTHRESMOD 1  
 RVTEMP 18 19 RVTEMPMOD 1

S1A 6 12 13 8 S1AMOD  
 S1B 13 12 13 8 S1BMOD  
 S2A 6 15 14 13 S2AMOD  
 S2B 13 15 14 13 S2BMOD

VBAT 22 19 DC 1

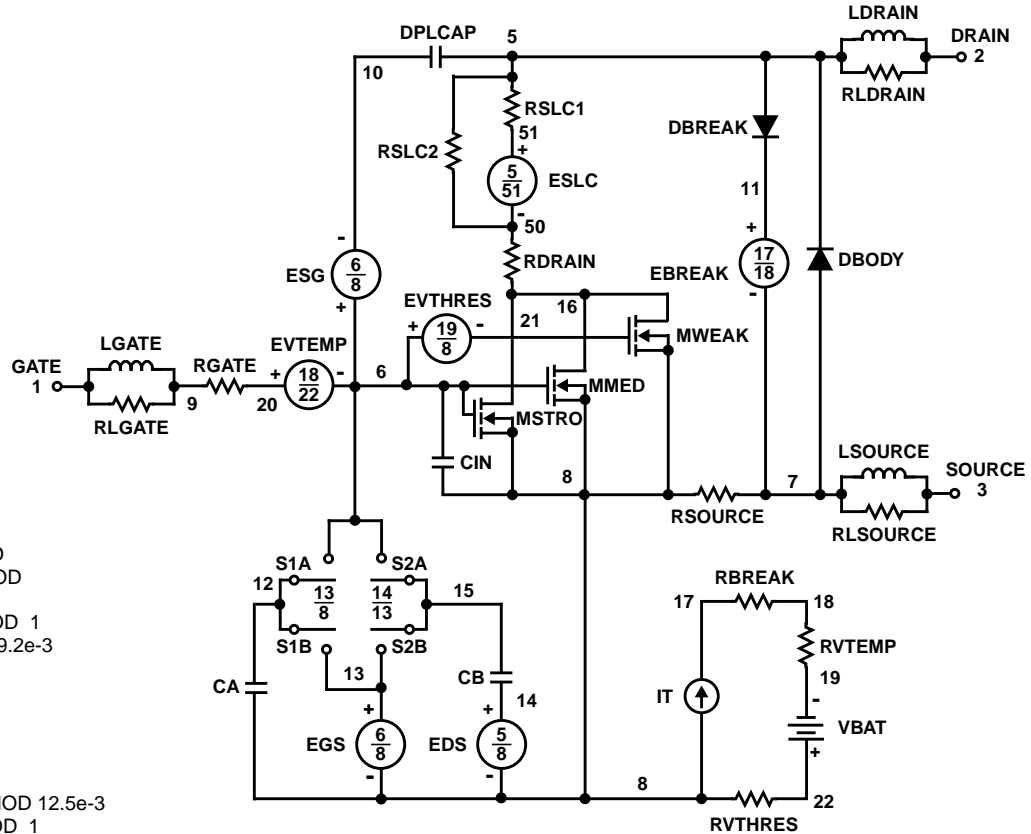
ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))\*(PWR(V(5,51)/(1e-6\*180),2.5))}

.MODEL DBODYMOD D (IS = 9.35e-13 RS = 1.39e-2 TRS1 = 1.12e-6 TRS2 = 1.05e-6 CJO = 9.85e-10 TT = 2.82e-8 M = 0.42)  
 .MODEL DBREAKMOD D (RS = 1.5e-1 TRS1 = 3.51e-3 TRS2 = -5e-5)  
 .MODEL DPLCAPMOD D (CJO = 4.4e-10 IS = 1e-30 N = 10 M = 0.6)  
 .MODEL MMEDMOD NMOS (VTO = 1.95 KP = 3.55 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 2.5)  
 .MODEL MSTROMOD NMOS (VTO = 2.23 KP = 29 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u)  
 .MODEL MWEAKMOD NMOS (VTO = 1.68 KP = 0.095 IS = 1e-30 N = 10 TOX = 1 L = 1u W = 1u RG = 25 RS = 0.1)  
 .MODEL RBREAKMOD RES (TC1 = 9.7e-4 TC2 = -5e-7)  
 .MODEL RDRAINMOD RES (TC1 = 5.8e-3 TC2 = 1.12e-5)  
 .MODEL RSLCMOD RES (TC1 = -9.92e-3 TC2 = -2.06e-5)  
 .MODEL RSOURCEMOD RES (TC1 = 3e-3 TC2 = 0)  
 .MODEL RVTHRESMOD RES (TC = -1.2e-3 TC2 = -5.42e-6)  
 .MODEL RVTEMPMOD RES (TC1 = -1.9e-3 TC2 = 1e-6)

.MODEL S1AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -7.0 VOFF = -1.5)  
 .MODEL S1BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -1.5 VOFF = -7.0)  
 .MODEL S2AMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = -0.8 VOFF = 0.6)  
 .MODEL S2BMOD VSWITCH (RON = 1e-5 ROFF = 0.1 VON = 0.6 VOFF = -0.8)

.ENDS

NOTE: For further discussion of the PSPICE model, consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.





**SPICE Thermal Model**

REV August 1998  
 HUF76113T3ST  
 Copper Area = 0.077 in<sup>2</sup>  
 C THERM1 th 8 1.9e-5  
 C THERM2 8 7 9.5e-4  
 C THERM3 7 6 1.9e-3  
 C THERM4 6 5 3.5e-3  
 C THERM5 5 4 2.0e-2  
 C THERM6 4 3 6.5e-2  
 C THERM7 3 2 2.4e-1  
 C THERM8 2 tl 9.0e-1

R THERM1 th 8 3.5e-3  
 R THERM2 8 7 3.1e-2  
 R THERM3 7 6 2.0e-1  
 R THERM4 6 5 8.0e-1  
 R THERM5 5 4 2.1  
 R THERM6 4 3 11  
 R THERM7 3 2 32  
 R THERM8 2 tl 66

**SABER Thermal Model**

Copper Area = 0.077 in<sup>2</sup>  
 template thermal\_model th tl  
 thermal\_c th, tl  
 {  
 ctherm.ctherm1 th 8 = 1.9e-5  
 ctherm.ctherm2 8 7 = 9.5e-4  
 ctherm.ctherm3 7 6 = 1.9e-3  
 ctherm.ctherm4 6 5 = 3.5e-3  
 ctherm.ctherm5 5 4 = 2.0e-2  
 ctherm.ctherm6 4 3 = 6.5e-2  
 ctherm.ctherm7 3 2 = 2.4e-1  
 ctherm.ctherm8 2 tl = 9.0e-1  
  
 rtherm.rtherm1 th 8 = 3.5e-3  
 rtherm.rtherm2 8 7 = 3.1e-2  
 rtherm.rtherm3 7 6 = 2.0e-1  
 rtherm.rtherm4 6 5 = 8.0e-1  
 rtherm.rtherm5 5 4 = 2.1  
 rtherm.rtherm6 4 3 = 11  
 rtherm.rtherm7 3 2 = 32  
 rtherm.rtherm8 2 tl = 66  
 }

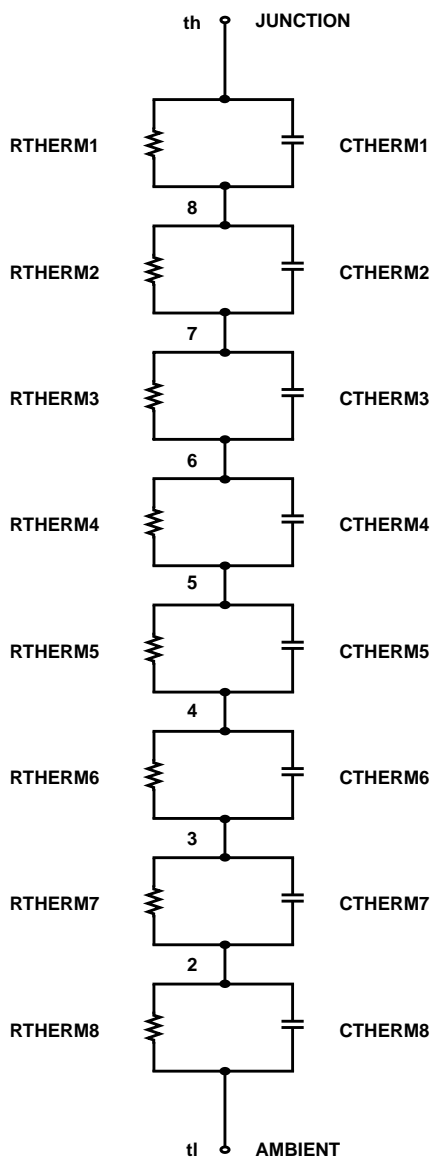


TABLE 1. THERMAL MODELS

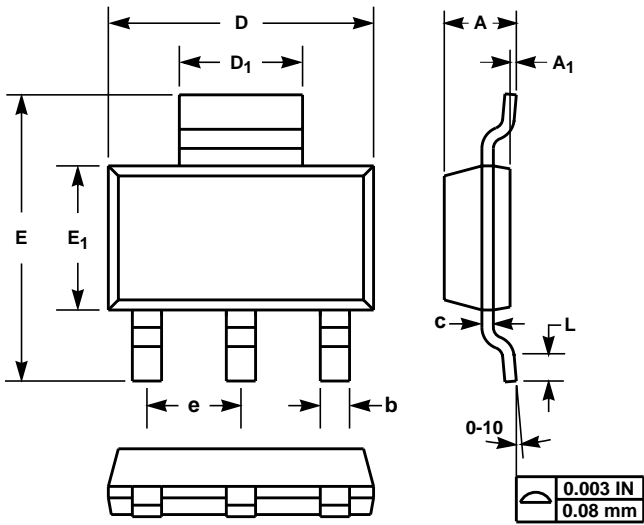
COMPONENT	0.077 in <sup>2</sup>	0.308 in <sup>2</sup>	0.535 in <sup>2</sup>	0.76 in <sup>2</sup>	0.996 in <sup>2</sup>
C THERM6	6.5e-2	6.7e-2	6.7e-2	6.7e-2	6.7e-2
C THERM7	2.4e-1	3.5e-1	3.5e-1	3.5e-1	3.5e-1
C THERM8	9.0e-1	1.7	1.9	2	2.4
R THERM6	11	9	9	9	9
R THERM7	32	18	16	15.5	14.5
R THERM8	66	45.5	40	36	31.5

All Intersil semiconductor products are manufactured, assembled and tested under **ISO9000** quality systems certification.

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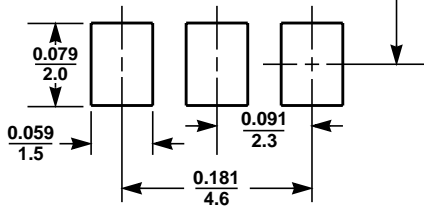
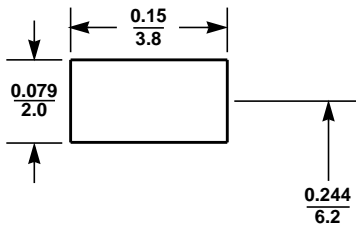
**SOT-223 (TO-261AA)**  
SMALL OUTLINE TRANSISTOR



SYMBOL	INCHES		MILLIMETERS		NOTES
	MIN	MAX	MIN	MAX	
A	0.063	0.070	1.60	1.78	-
A <sub>1</sub>	0.0008	0.004	0.02	0.10	-
b	0.026	0.033	0.65	0.85	-
c	0.010	0.014	0.25	0.35	-
D	0.248	0.264	6.30	6.70	-
D <sub>1</sub>	0.116	0.124	2.95	3.15	-
E	0.264	0.287	6.70	7.30	-
E <sub>1</sub>	0.130	0.146	3.30	3.70	2
e	0.0905 BSC		2.30 BSC		-
L	0.036	-	0.91	-	3

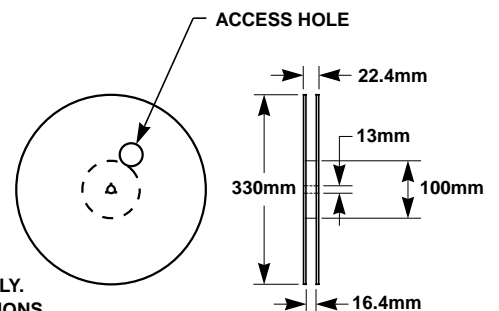
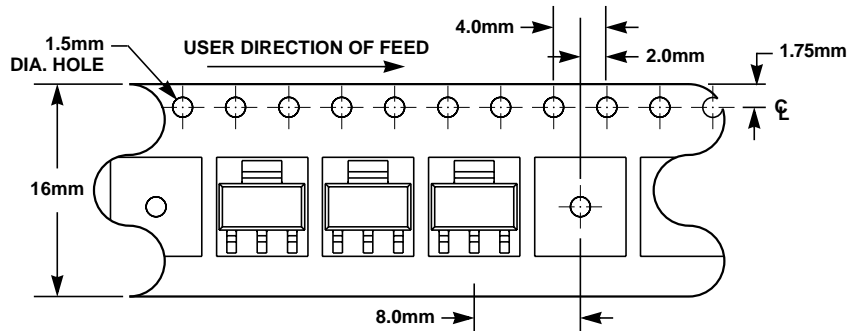
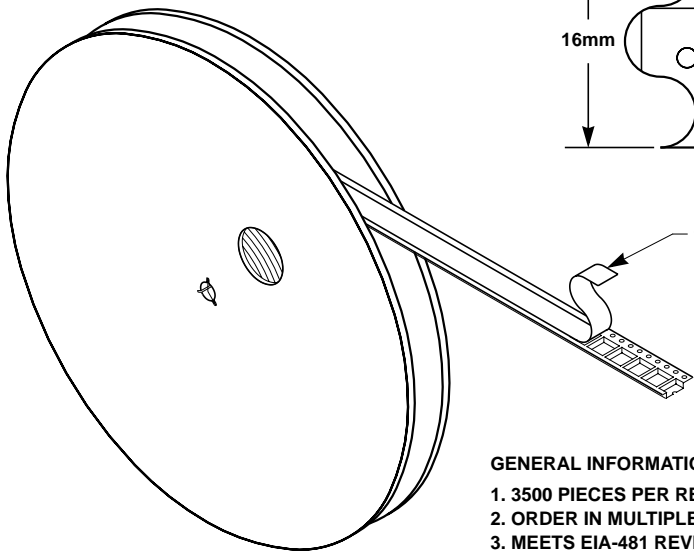
NOTES:

1. All dimensions are within the allowable dimensions of Rev. A of JEDEC TO-261 outline dated 1-90.
2. Dimension "E<sub>1</sub>" does not include inter-lead flash or gate burr protrusions. Inter-lead flash and protrusions shall not exceed 0.010 inches (.25mm) per side.
3. "L" is the length of terminal for soldering.
4. Controlling dimension: Millimeter.
5. Revision 5 dated 5-99.



MINIMUM RECOMMENDED FOOTPRINT FOR SURFACE MOUNTED APPLICATIONS

**SOT-223**  
16mm TAPE AND REEL



GENERAL INFORMATION

1. 3500 PIECES PER REEL.
2. ORDER IN MULTIPLES OF FULL REELS ONLY.
3. MEETS EIA-481 REVISION "A" SPECIFICATIONS.